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| <b>Search Notes</b><br> | <b>Application/Control No.</b><br>10582503 | <b>Applicant(s)/Patent Under Reexamination</b><br>IMANAKA ET AL. |
|  | <b>Examiner</b><br>ALEXANDER C WITKOWSKI   | <b>Art Unit</b><br>2853  |

| SEARCHED |          |      |          |
|----------|----------|------|----------|
| Class    | Subclass | Date | Examiner |
|          |          |      |          |

| SEARCH NOTES                                   |            |          |
|--|------------|----------|
| Search Notes                                   | Date       | Examiner |
| Stephen D. Meier, Supervisory Patent Examiner. | 09/24/2008 | ACW      |
| Limited classification search: 347/ 62, 64     | 09/24/2008 | ACW      |
| Text search. See search history.               | 09/24/2008 | ACW      |

| INTERFERENCE SEARCH |          |      |          |
|---------------------|----------|------|----------|
| Class               | Subclass | Date | Examiner |
|                     |          |      |          |

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